

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Eric NEYRET et al.

Confirmation No.:

Application No: To be assigned

Group Art Unit:

Filing Date:

Examiner:

For: METHOD FOR REDUCING FREE SURFACE
ROUGHNESS OF A SEMICONDUCTOR
WAFER

Atty. Docket No.: 4717-8300

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

Sir:

Pursuant to applicants' duty of disclosure under 37 C.F.R. 1.56, eleven (11) references for the Examiner's review and consideration are listed on the enclosed Form PTO-1449. A copy of an International Search Report of a counterpart application is also enclosed.

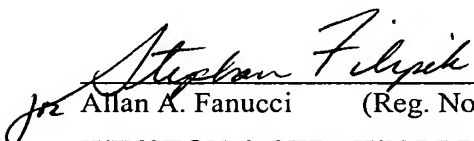
Pursuant to the recent rule change in the Official Gazette, copies of the U.S. references are not submitted. It is respectfully requested that this references be made of record in this application by the Examiner's completion and return of the PTO Form 1449.

It is noted that EP 1,158,581 is a counterpart application to WO 01/28000; FR 2,797,713 is a counterpart application to WO 01/15215; and US 6,406,450 is a counterpart application to FR 2,777,115.

No fee or certification is believed to be due for this submission since the references are being submitted concurrent with the filing of this application. Should any fees be required, however, please charge such fees to **Winston & Strawn** Deposit Account No. 501-814.

Respectfully submitted,

Date: December 30, 2003


for Allan A. Fanucci (Reg. No. 30,256)

WINSTON & STRAWN LLP
CUSTOMER NO. 28765
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Enclosure

LIST OF REFERENCES CITED BY APPLICANT <i>(Use several sheets if necessary)</i>					ATTY. DOCKET NO.:		APPLICATION NO.:	
					4717-8300			
					APPLICANT:			
					Eric NEYRET et al.			
					FILING DATE:		GROUP:	
U.S. PATENT DOCUMENTS								
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	AA	5,374,564	12/1994	Bruel	437	24		
	AB	6,171,965	1/2001	Kang et al.	438	695		
	AC	6,403,450	6/2002	Maleville et al.	438	471		
	AD	6,573,159	6/2003	Kobayashi et al.	438	471		
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AE	FR 2777115 (with English abstract)	10/1999	France			X	
	AF	FR 2797713 (with English abstract)	2/2001	France			X	
	AG	WO 01/15215 (with English abstract)	3/2001	PCT			X	
	AH	WO 01/28000 (with English abstract)	4/2001	PCT			X	
	AI	EP 1045448	10/2000	Europe				
	AJ	EP 1061565	12/2000	Europe				
	AK	EP 1158581	11/2001	Europe				
OTHER REFERENCES <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>								
EXAMINER					DATE CONSIDERED			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								